BT151X-500C

SCR

24 July 2012 Product data sheet

1. Product profile

1.1 General description

Planar passivated Silicon Controlled Rectifier (SCR) in a SOT186A (TO-220F) "full pack" plastic package intended for use in applications requiring good bidirectional blocking voltage capability and high thermal cycling performance.

1.2 Features and benefits

- Good bidirectional blocking voltage capability
- High thermal cycling performance
- Isolated mounting base package
- Planar passivated for voltage ruggedness and reliability

1.3 Applications

- Capacitive Discharge Ignition (CDI)
- Crowbar protection
- Inrush protection
- Motor control
- Voltage regulation

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V_{DRM}	repetitive peak off-state voltage			-	-	500	V
V_{RRM}	repetitive peak reverse voltage			-	-	500	V
I_{TSM}	non-repetitive peak on-state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5		-	-	100	A
$I_{T(RMS)}$	RMS on-state current	half sine wave; $T_h \leq 69$ °C; Fig. 1; Fig. 2; Fig. 3		-	-	12	A
Static characteristics							
I_{GT}	gate trigger current	V_D = 12 V; I_T = 0.1 A; T_j = 25 °C; Fig. 7		-	2	15	mA

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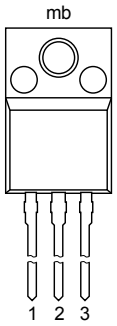
2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	 TO-220F (SOT186A)	
2	A	anode		
3	G	gate		
mb	n.c.	mounting base; isolated		

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BT151X-500C	TO-220F	plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 "full pack"	SOT186A

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage			-	500	V
V_{RRM}	repetitive peak reverse voltage			-	500	V
$I_{T(AV)}$	average on-state current	half sine wave; $T_h \leq 69$ °C		-	7.5	A
$I_{T(RMS)}$	RMS on-state current	half sine wave; $T_h \leq 69$ °C; Fig. 1; Fig. 2; Fig. 3		-	12	A
I_{TSM}	non-repetitive peak on-state current	half sine wave; $T_{j(init)} = 25$ °C; $t_p = 10$ ms; Fig. 4; Fig. 5		-	100	A
		half sine wave; $T_{j(init)} = 25$ °C; $t_p = 8.3$ ms		-	110	A
I^2t	I^2t for fusing	$t_p = 10$ ms; SIN		-	50	A^2s
dI_T/dt	rate of rise of on-state current	$I_T = 20$ A; $I_G = 50$ mA; $dI_G/dt = 50$ mA/µs		-	50	A/µs
I_{GM}	peak gate current			-	2	A

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Symbol	Parameter	Conditions		Min	Max	Unit
V_{RGM}	peak reverse gate voltage			-	5	V
P_{GM}	peak gate power			-	5	W
$P_{G(AV)}$	average gate power	over any 20 ms period		-	0.5	W
T_{stg}	storage temperature			-40	150	°C
T_j	junction temperature			-	125	°C

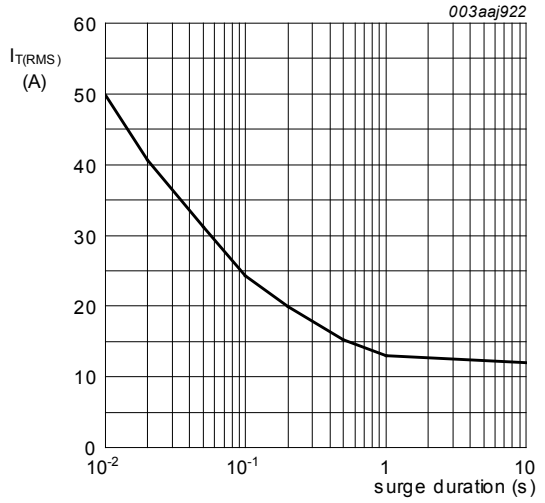

Fig. 1. RMS on-state current as a function of surge duration; maximum values

$f = 50\ Hz;\quad T_h = 69\ °C$

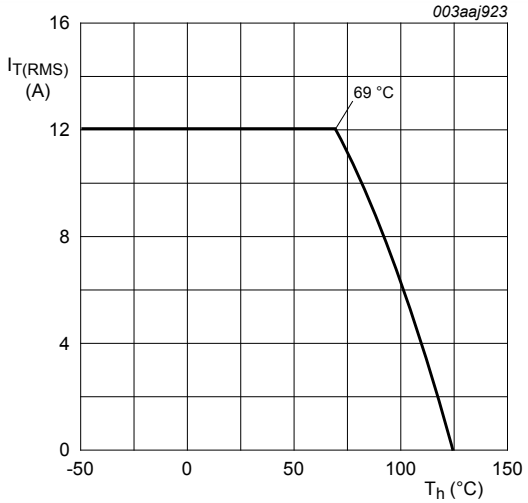

Fig. 2. RMS on-state current as a function of heatsink temperature; maximum values

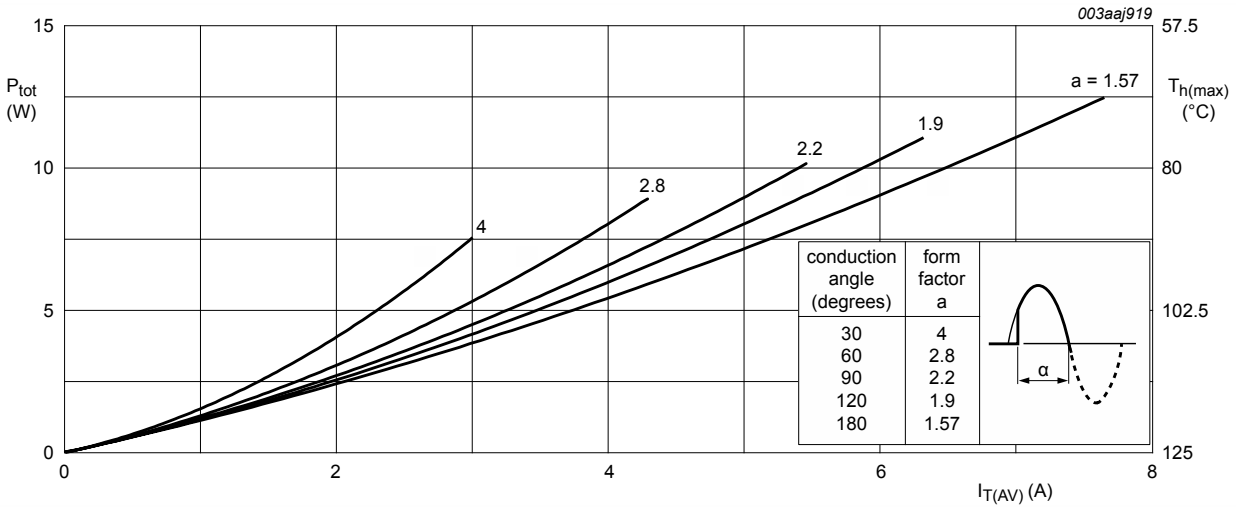

Fig. 3. Total power dissipation as a function of average on-state current; maximum values

α = conduction angle a = form factor = $I_{T(RMS)} / I_{T(AV)}$

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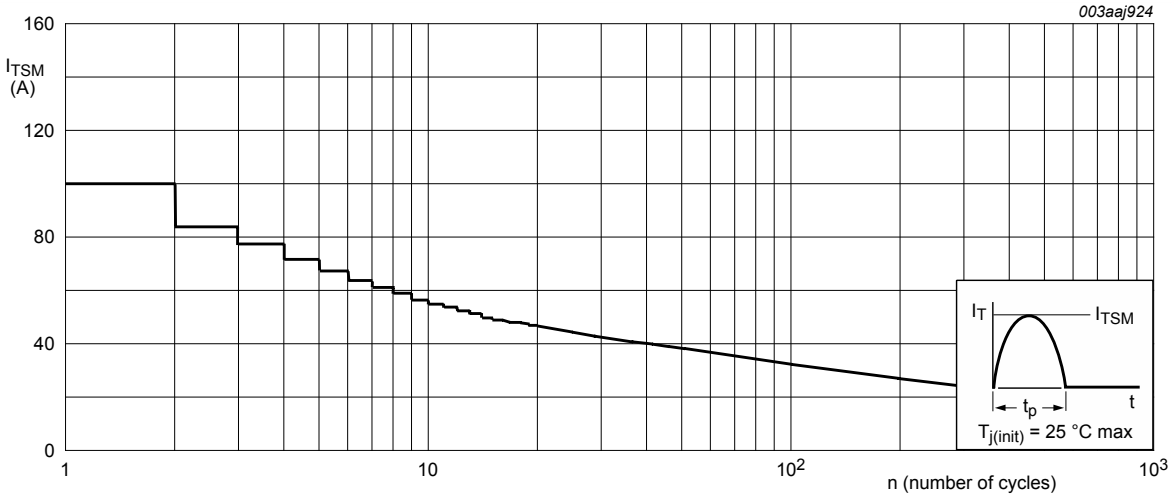

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

f = 50 Hz

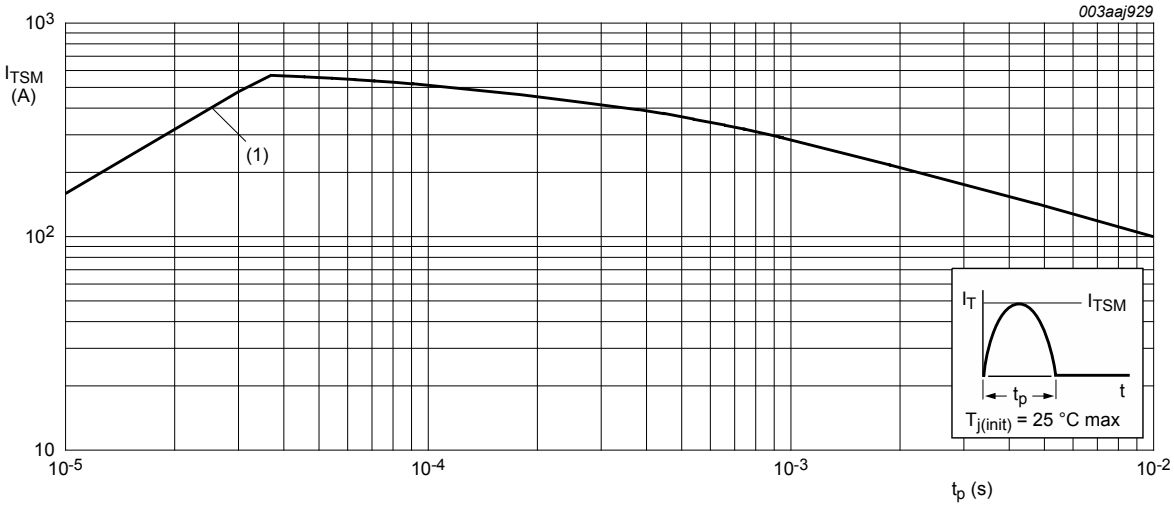

Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

$t_p \leq 10$ ms; (1) dI_T/dt limit

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-h)}$	thermal resistance from junction to heatsink	with heatsink compound; Fig. 6		-	-	4.5	K/W
		without heatsink compound; Fig. 6		-	-	6.5	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air		-	55	-	K/W

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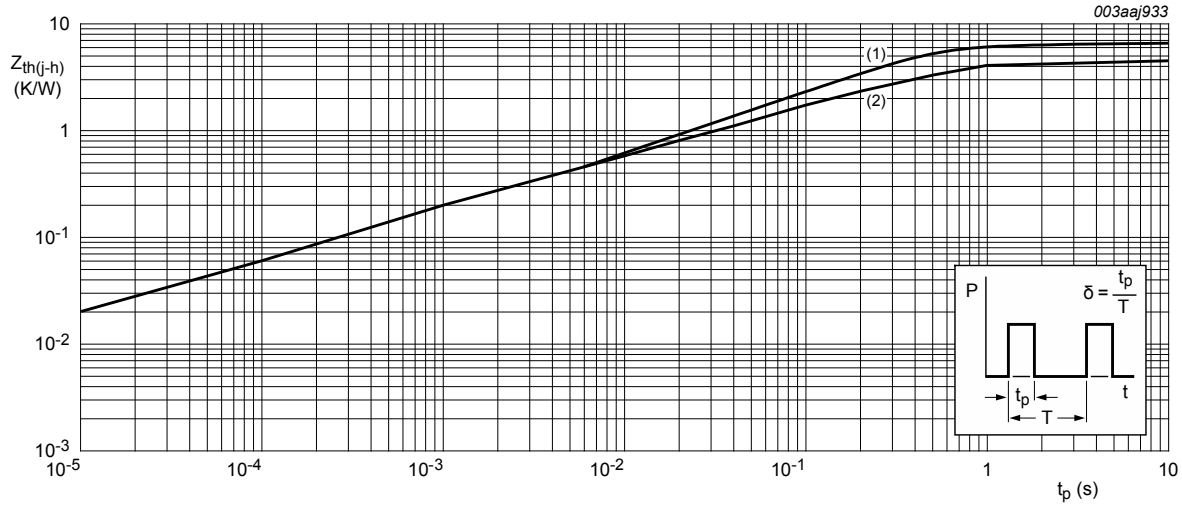

(1) Without heatsink compound
(2) With heatsink compound

Fig. 6. Transient thermal impedance from junction to heatsink as a function of pulse width

6. Isolation characteristics

Table 6. Isolation characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$V_{isol(RMS)}$	RMS isolation voltage	from all terminals to external heatsink; sinusoidal waveform; clean and dust free ; 50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; T_h = 25 °C		-	-	2500	V
C_{isol}	isolation capacitance	from anode to external heatsink ; f = 1 MHz; T_h = 25 °C		-	10	-	pF

7. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
I_{GT}	gate trigger current	V_D = 12 V; I_T = 0.1 A; T_j = 25 °C; Fig. 7		-	2	15	mA
I_L	latching current	V_D = 12 V; I_G = 0.1 A; T_j = 25 °C; Fig. 8		-	10	40	mA
I_H	holding current	V_D = 12 V; T_j = 25 °C; Fig. 9		-	7	20	mA
V_T	on-state voltage	I_T = 23 A; T_j = 25 °C; Fig. 10		-	1.4	1.75	V
V_{GT}	gate trigger voltage	V_D = 12 V; I_T = 0.1 A; T_j = 25 °C; Fig. 11		-	0.6	1.5	V
		V_D = 500 V; I_T = 0.1 A; T_j = 125 °C; Fig. 11		0.25	0.4	-	V

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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
I_D	off-state current	V_D = 500 V; T_j = 125 °C		-	0.1	0.5	mA
I_R	reverse current	T_j = 125 °C; V_R = 500 V		-	0.1	0.5	mA
Dynamic charateristics							
dV_D/dt	rate of rise of off-state voltage	V_{DM} = 335 V; T_j = 125 °C; R_{GK} = 100 Ω; exponential waveform; (V_{DM} = 67% of V_{DRM}); Fig. 12		200	1000	-	V/µs
		V_{DM} = 335 V; T_j = 125 °C; exponential waveform; gate open circuit; (V_{DM} = 67% of V_{DRM}); Fig. 12		50	130	-	V/µs
t_{gt}	gate-controlled turn-on time	I_{TM} = 40 A; V_D = 500 V; I_G = 100 mA; dI_G/dt = 5 A/µs; T_j = 25 °C		-	2	-	µs
t_q	commutated turn-off time	V_{DM} = 335 V; T_j = 125 °C; I_{TM} = 20 A; V_R = 25 V; $(dI_T/dt)_M$ = 30 A/µs; dV_D/dt = 50 V/µs; R_{GK} = 100 Ω; (V_{DM} = 67% of V_{DRM})		-	70	-	µs

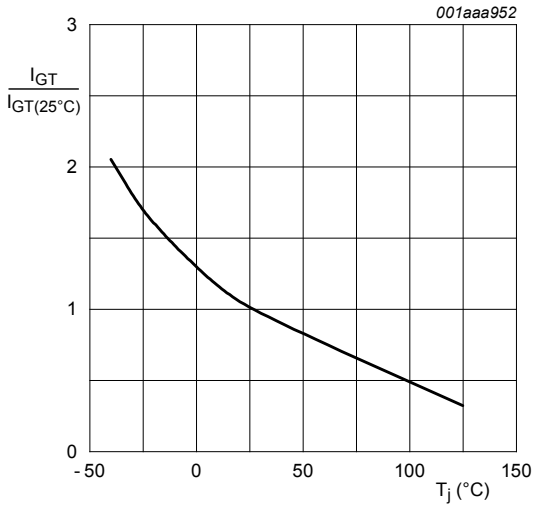

Fig. 7. Normalized gate trigger current as a function of junction temperature

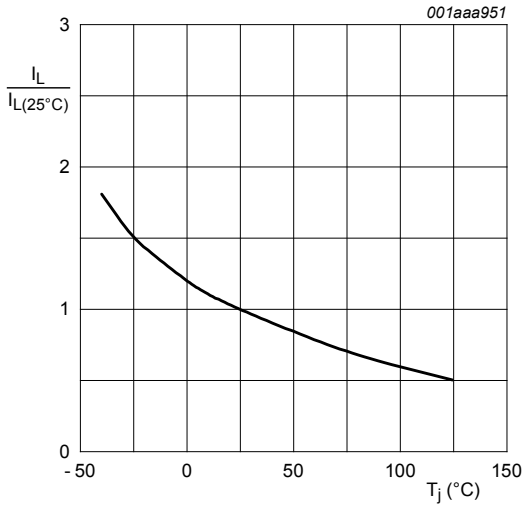

Fig. 8. Normalized latching current as a function of junction temperature

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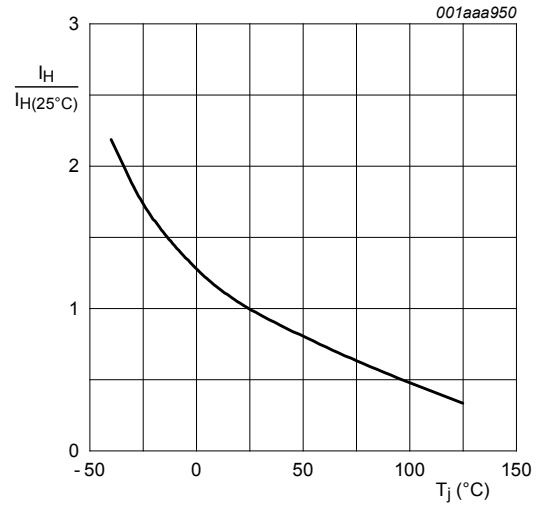
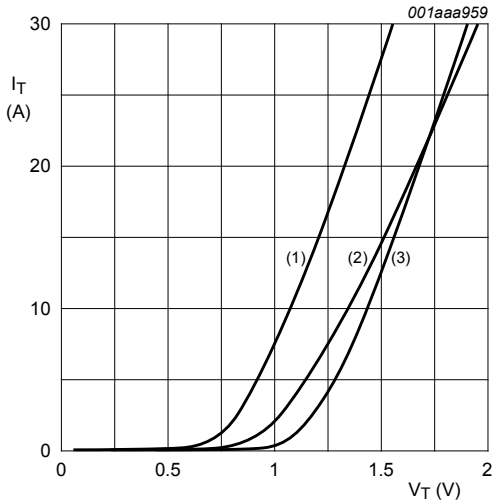


Fig. 9. Normalized holding current as a function of junction temperature



V_o = 1.06 V; R_s = 0.0304 Ω

(1) T_j = 125 °C; typical values

(2) T_j = 125 °C; maximum values

(3) T_j = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

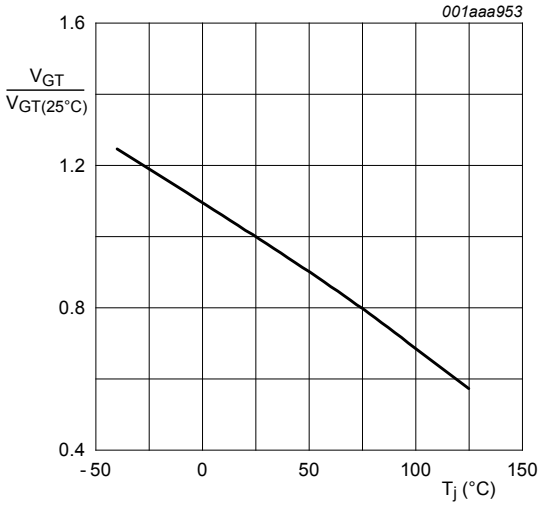
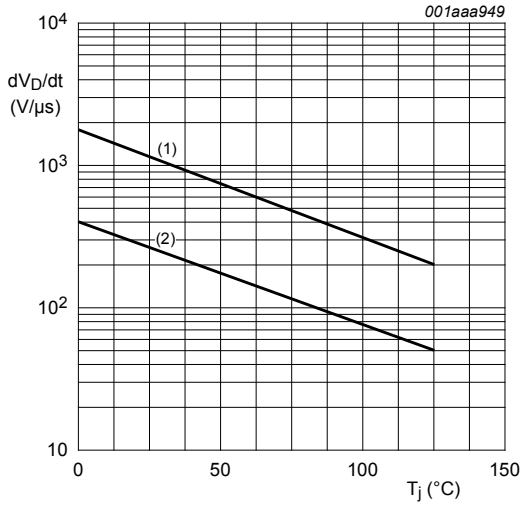


Fig. 11. Normalized gate trigger voltage as a function of junction temperature



(1) R_{GK} = 100 Ω;

(2) gate open circuit

Fig. 12. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

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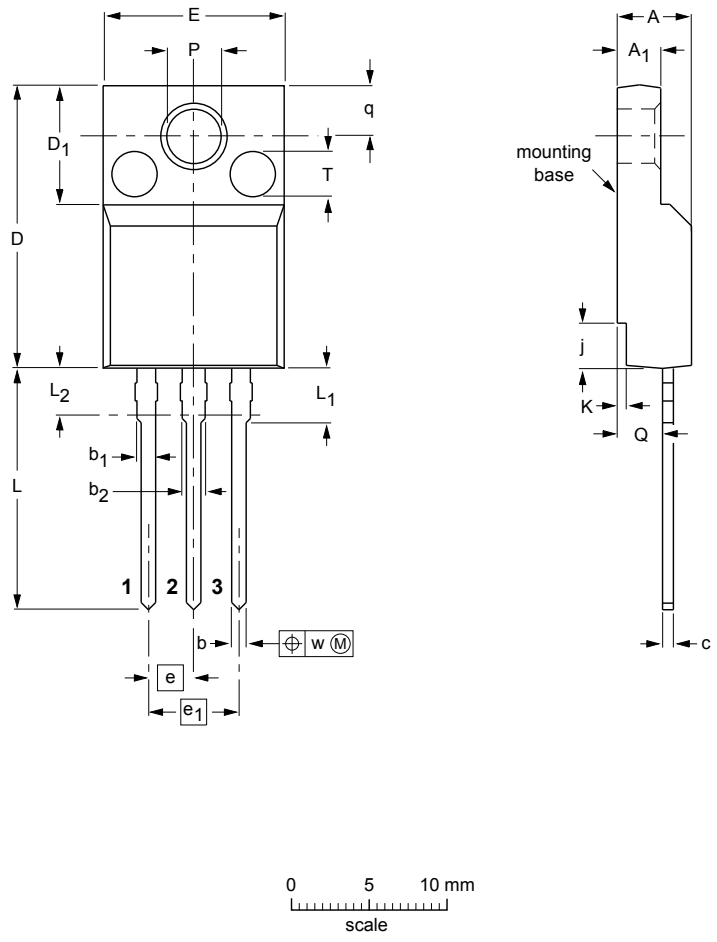
8. Package outline

Plastic single-ended package; isolated heatsink mounted;
1 mounting hole; 3-lead TO-220 'full pack'

SOT186A



DIMENSIONS (mm are the original dimensions)

UNIT	A	A_1	b	b_1	b_2	c	D	D_1	E	e	e_1	j	K	L	L_1	L_2 (1) max.	P	Q	q	T (2)	w
mm	4.6 4.0	2.9 2.5	0.9 0.7	1.1 0.9	1.4 1.0	0.7 0.4	15.8 15.2	6.5 6.3	10.3 9.7	2.54	5.08	2.7 1.7	0.6 0.4	14.4 13.5	3.30 2.79	3	3.2 3.0	2.6 2.3	3.0 2.6	2.5	0.4

Notes

1. Terminal dimensions within this zone are uncontrolled.
2. Both recesses are # 2.5 × 0.8 max. depth

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT186A		3-lead TO-220F				~~02-04-09~~ 06-02-14

Fig. 13. TO-220F (SOT186A)

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